

FDD6630A

30V N-Channel PowerTrench MOSFET

General Description

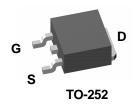
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low RDS(ON) and fast switching speed.

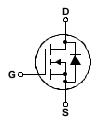
Applications

- DC/DC converter
- Motor drives

Features

- 21 A, 30 V $R_{DS(ON)} = 35 \text{ m}\Omega$ @ $V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 50 \text{ m}\Omega$ @ $V_{GS} = 4.5 \text{ V}$
- Low gate charge (5nC typical)
- · Fast switching
- High performance trench technology for extremely low R_{DS(ON)}





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		30	V
V _{GSS}	Gate-Source Voltage		±20	V
I _D	Drain Current - Continuous	(Note 3)	21	A
	- Pulsed	(Note 1a)	100	
P _D	Power Dissipation	(Note 1)	28	W
		(Note 1a)	3.2	
		(Note 1b)	1.3	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +175	°C

Thermal Characteristics

R ₀ JC	Thermal Resistance, Junction-to-Case	(Note 1)	4.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1b)	96	°C/W

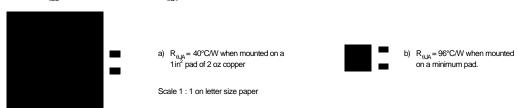
Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDD6630A	FDD6630A	13"	16mm	2500 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Sc	ource Avalanche Ratings (Note	2)			ı	I
W _{DSS}	Drain-Source Avalanche Energy	Single Pulse, V _{DD} = 15 V			55	mJ
l _{AR}	Drain-Source Avalanche Current				7.6	Α
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		23		mV/°C
l _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ
IGSSF	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
IGSSR	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1	1.7	3	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		-4		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V}, I_D = 7.6 \text{ A}$ $V_{GS} = 4.5 \text{ V}, I_D = 6.3 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 7.6 \text{ A}, T_J = 125^{\circ}\text{C}$		28 40 44	35 50 58	mΩ
I _{D(on)}	On–State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	20			Α
g FS	Forward Transconductance	$V_{DS} = 5 \text{ V}, \qquad I_{D} = 7.6 \text{ A}$		13		S
Dynamic	Characteristics			l		
Ciss	Input Capacitance	$V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		462		pF
Coss	Output Capacitance	f = 1.0 MHz		113		pF
C _{rss}	Reverse Transfer Capacitance			40		pF
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 15 \text{ V}, \qquad I_D = 1 \text{ A},$		5	11	ns
t _r	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		8	17	ns
t _{d(off)}	Turn-Off Delay Time			17	28	ns
t _f	Turn-Off Fall Time			13	24	ns
Qg	Total Gate Charge	$V_{DS} = 15 \text{ V}, \qquad I_{D} = 7.6 \text{ A},$		5	7	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 V$		2		nC
Q_{gd}	Gate-Drain Charge			1.4		nC
Drain-Se	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Source	Diode Forward Current			2.7	Α
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 2.7 \text{ A}$ (Note 2)		0.8	1.2	V

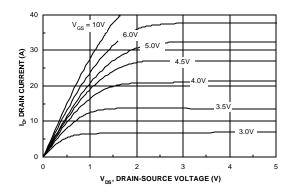
Notes:

1. R_{Q,A} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{Q,C} is guaranteed by design while R_{Q,CA} is determined by the user's board design.



- 2. Pulse Test: Pulse Width < $300\mu s,$ Duty Cycle < 2.0%
- 3. Maximum current is calculated as: $\sqrt{\frac{P_D}{R_{Roc,roll}}}$ where P_D is maximum power dissipation at $T_C = 25^{\circ}C$ and $R_{DS(on)}$ is at $T_{J(max)}$ and $V_{GS} = 10V$. Package current limitation is 21A

Typical Characteristics

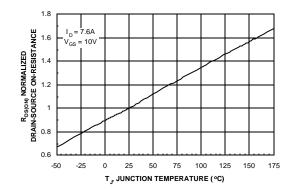


R_{DS(ON)} NORMALIZED DRAIN-SOURCE ON-RESISTANCE -6.0V 10V **-**0.5 I_D, DRAIN CURRENT (A)

2.5

Figure 1. On-Region Characteristics.

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.



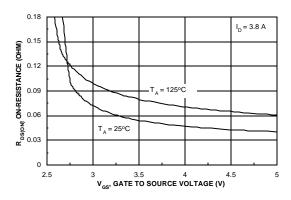
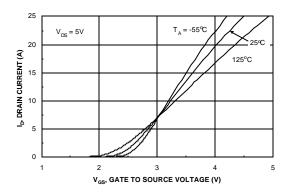


Figure 3. On-Resistance Variation with Temperature.

Figure 4. On-Resistance Variation with Gate-to-Source Voltage.



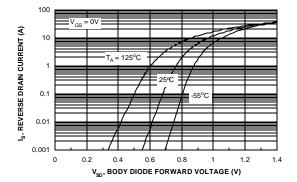
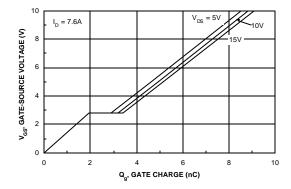


Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



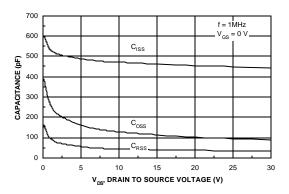
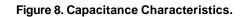
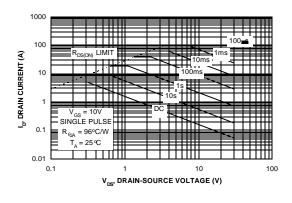


Figure 7. Gate Charge Characteristics.





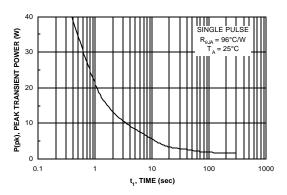


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

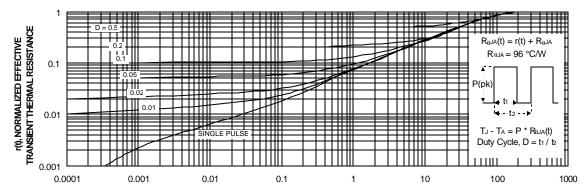


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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